

Notice of References Cited	Application/Control No. 10/807,321		Applicant(s)/Patent Under Reexamination KAWAMURA, TAKUYA	
	Examiner ANDREW WENDELL		Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0142059	06-2006	Ishiguro et al.	455/556.1
*	B	US-2006/0009259	01-2006	Tanaka, Hiroshi	455/556.1
*	C	US-2005/0130702	06-2005	Saburi et al.	455/556.1
*	D	US-2004/0242250	12-2004	Sasai et al.	455/502
*	E	US-2002/0102938	08-2002	Tsubaki et al.	455/3.06
*	F	US-2002/0032005	03-2002	Yoshida, Shigeo	455/41
*	G	US-6,907,225	06-2005	Wilkinson, Jeffrey Miles	455/41.2
*	H	US-2005/0036509	02-2005	Acharya et al.	370/466
*	I	US-2002/0112026	08-2002	Fridman et al.	709/217
*	J	US-7,035,667	04-2006	Ido, Tetsuo	455/556.1
*	K	US-6,736,726	05-2004	Miura, Katsuhiko	463/41
*	L	US-2004/0160623	08-2004	Strittmatter et al.	358/001.15
*	M	US-2007/0046998	03-2007	Ohnishi, Shinji	358/003.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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